

**Issue Classification**

Devin Hanan 12/11/05  
Devin Hanan 12/11/2005  
(Assistant Examiner) (Date)

Edward K. Look 12/14/05  
EDWARD K. LOOK  
SUPERVISORY PATENT EXAMINER  
TECHNOLOGY CENTER 3700  
(Primary Examiner) (Date)

**Total Claims Allowed: 24**

O.G. Print Claim(s)	O.G. Print Fig
18	6

☐ Claims renumbered in the same order as presented by applicantCPA☐ T.D.□ R.1.47[illegible]